

Laboratory test devices and test adapters for ICT and function test

The laboratory test devices and test adapters for In-circuit test (ICT) and function test are designed, manufactured and constructed according to individual customer requirements. Based on the two basic concepts, the test material can be contacted either mechanically or pneumatically and can possibly be flashed.

To test a variety of circuit boards, the laboratory devices can be equipped with exchangeable test adapters (contact units). The use of standardized interfaces provides quick connection to pneumatic and electrical control cabinets or in-line systems. One exchangeable contact unit and one VPC interface can be flexibly used for multiple test scenarios such as in-line hot function test (HFT) or in laboratory devices function tests or HFTs.

For an optimized and soft contact of the test material IMAK uses a quickly available range of spring contact pins and high current pins with spring forces according to the test material.

The used materials are checked for ESD compliance during the development of all components (downholder, locking, test piece fixture, exchangeable contact unit, housing).

Performance overview ICT Adapter

Soft contact of assembled PCBs

Pneumatic, mechanical and in-line adaptations

Spring downholder system

Standardized VPC interface (customizable)

Quickly available range of contact-, high current-, switching pins

Equipment with barcode readers and stroke counter is possible

Performance overview function test Adapter

Contacting of PCB assemblies and capped components

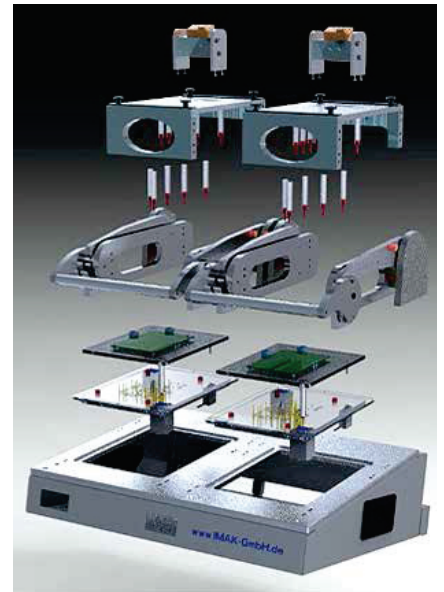
Function test in high voltage range by ceramic fixtures and purpose-developed high-current terminals (see separate data sheets)

Flashing the memory modules

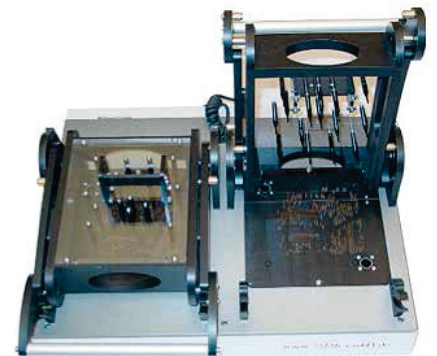
Pneumatic, mechanical and inline adaptations

Gentle fixing and testing of the test piece

Equipment with barcode readers and stroke counter is possible



Structure of the ICT device from the top: barcode reader, downholder with contact pins, locking, test piece fixture, exchangeable contact unit, housing



ICT laboratory test device



Exchangeable contact unit and VPC interface for multiple test scenarios, left HFT in-line, right laboratory test device for functional test / HFT